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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/810,419	03/26/2004	Lahir Shaik Adam	TI-36390	8933
23494	7590 06/22/2005		EXAMINER	
TEXAS INSTRUMENTS INCORPORATED			DANG, PHUC T	
	P O BOX 655474, M/S 3999 DALLAS, TX 75265		ART UNIT	PAPER NUMBER
ŕ			2818	

DATE MAILED: 06/22/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	Applicant(s)			
	10/810,419	ADAM ET AL.	ADAM ET AL.			
Office Action Summary	Examiner	Art Unit	T (and			
	PHUC T. DANG	2818				
The MAILING DATE of this communication appeared for Reply	ppears on the cover s	sheet with the correspondence a	address			
A SHORTENED STATUTORY PERIOD FOR REP THE MAILING DATE OF THIS COMMUNICATION - Extensions of time may be available under the provisions of 37 CFR 1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a re - If NO period for reply is specified above, the maximum statutory perio Failure to reply within the set or extended period for reply will, by statu- Any reply received by the Office later than three months after the mail earned patent term adjustment. See 37 CFR 1.704(b).	1.136(a). In no event, however, ply within the statutory minim d will apply and will expire SI tte, cause the application to b	er, may a reply be timely filed num of thirty (30) days will be considered tim X (6) MONTHS from the mailing date of this secome ABANDONED (35 U.S.C. § 133).				
Status						
1) Responsive to communication(s) filed on ele	ction filed June 1, 20	0 <u>05</u> .				
2a) ☐ This action is FINAL . 2b) ☑ Th						
	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims						
 4) Claim(s) 1-25 is/are pending in the application 4a) Of the above claim(s) 18-25 is/are withdress 5) Claim(s) 10-17 is/are allowed. 6) Claim(s) 1-8 is/are rejected. 7) Claim(s) 9 is/are objected to. 8) Claim(s) are subject to restriction and 	awn from considerat					
Application Papers						
9) ☐ The specification is objected to by the Examin 10) ☑ The drawing(s) filed on 26 March 2004 is/are Applicant may not request that any objection to the Replacement drawing sheet(s) including the correction of the oath or declaration is objected to by the I	: a)⊠ accepted or be the drawing(s) be held in the ection is required if the	n abeyance. See 37 CFR 1.85(a). drawing(s) is objected to. See 37 (CFR 1.121(d).			
Priority under 35 U.S.C. § 119						
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority docume 2. Certified copies of the priority docume 3. Copies of the certified copies of the priority docume application from the International Bure * See the attached detailed Office action for a list	nts have been receiv nts have been receiv iority documents hav eau (PCT Rule 17.2(a	ved. ved in Application No ve been received in this Nationa a)).	al Stage			
Attachment(s)						
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/0 Paper No(s)/Mail Date	P (8) 5) D	nterview Summary (PTO-413) aper No(s)/Mail Date lotice of Informal Patent Application (P	TO-152)			

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DETAILED ACTION

Restriction/election

1. Applicant's election without traverse of Group I (claims 1-17) filed on June 1, 2005, drawn to a method for fabricating a tri-gate semiconductor device and withdrawn Group II (claims 18-25).

Applicants have the right to file a divisional application covering the subject matter of the non-elected claims.

Specification

2. The specification has been checked to the extent necessary to determine the presence of all possible minor errors. However, the applicant's cooperation is requested in correcting any errors of which applicant may become aware in the specification.

Claim Rejections - 35 USC § 102

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(f) or (g) prior art under 35 U.S.C. 103(a).

3. Claims 1, 4-6, and 8 are rejected under 35 U.S.C. 102 (b) as being anticipated by Chang et al., hereinafter "Chang" (U.S. Patent No. 6,204,159 B1).

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Regarding claims 1, Chang discloses a method for forming a NAND gate flash memory device comprising:

forming a high voltage gate dielectric layer (48, Fig. 7) over a semiconductor substrate (30, Fig. 7);

implanting a low dose of nitrogen (col. 8, lines 34-35) into the semiconductor substrate (30, Fig. 7) in a low voltage core region (34, Fig. 8); and

forming a low voltage core gate dielectric layer (58, Fig. 7) over the low voltage core region (34, Fig. 8), including forming an intermediate core gate dielectric layer (40, Figs. 6-11) over an intermediate core region (46, Fig. 11).

Regarding claims 4-5, Chang discloses the thickness of the gate dielectric layers are applied in the process [col. 5, lines 49-52 and col. 8, lines 55+].

Regarding claim 6, Chang discloses forming the low voltage core gate dielectric layer (58, Fig. 7) and the intermediate core dielectric layer (40, Fig. 7) is conducted in the presence of an environment of nitrogen [col. 8, lines 27-38].

Regarding claim 8, Chang discloses forming a first gate over the high voltage gate dielectric layer, forming a second gate over the low voltage core gate dielectric layer and forming a third gate over the intermediate core dielectric layer [Fig. 12].

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior

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art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

4. Claims 2-3 and 7 are rejected under 35 U.S.C. 103(a) as being unpatentable over Chang in view of An et al., hereinafter "An" (U.S. Patent No. 6,165,849).

Chang discloses all the features of the claimed invention as discussed above, but does not disclose the implanting of the low dose ranges of nitrogen into the substrate.

An, however, discloses the implanting of the low dose ranges of nitrogen into the substrate [col. 3, lines 18-29].

It would have been obvious to one having ordinary skilled in the art at the time the invention was made to modify the above discussed teaching of Chang as taught by An for a purpose of improving the reliability in the processing.

Allowable Subject Matter

5. Claims 10-17 would be allowed.

The following is a statement of reason for the indication of allowable subject matter:

Claims 10-17 are considered allowable since the prior art of record and the considered pertinent to the applicant's disclosure does not teach or suggest the claimed invention having a step of forming interconnects extending through dielectric layers located over first, second, and third transistor gates to interconnect the first, second and third transistor gates to form an operative tri-gate integrated circuit as cited in claim 10.

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Claim 9 is objected to as being dependent upon a rejected base claim, but would be

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allowable if rewritten in independent form including all of the limitations of the base claim and

any intervening claim.

None of the prior art made of record does not disclose a step of forming the second gate

includes forming the second gate such that a concentration of nitrogen within the second gate is

substantially uniform through the second gate.

Conclusion

6. Any inquiry concerning this communication or earlier communications from the examiner

should be directed to Phuc T. Dang whose telephone number is (571) 272-1776. The examiner

can normally be reached on 8:00 am-5:00 pm.

7. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor,

David C. Nelms can be reached on (571) 272-1787. The fax phone numbers for the organization

where this application or proceeding is assigned are 703-872-9306 for regular communications

and After Final communications.

8. Any inquiry of a general nature or relating to the status of this application or proceeding

should be directed to the receptionist whose telephone number is 703-308-0956.

Sanggshur

Phuc T. Dang

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Primary Examiner

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